Edge -TCT measurements on irradiated HV - CMOS sensors

A summer student presentation by Constantin Weisser

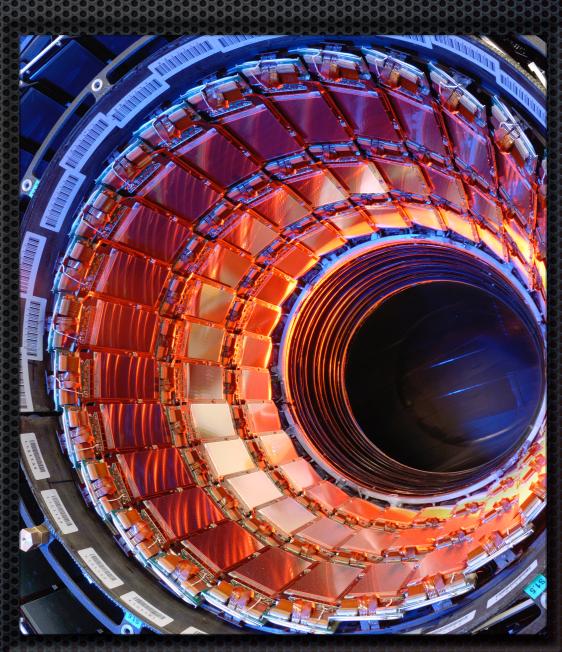
I came to CERN and built a box.



Actually, lonly drilled holes into it.

Background

- 1. Pixel detectors in LHC are used for Particle Reconstruction
- With the new upgrades a higher granularity of sensors is needed and particles will exert 10 times more fluence
- 3. Detectors are not perfect and radiation can induce defects in the crystal lattice
- We need cost efficient and radiation hard detectors!

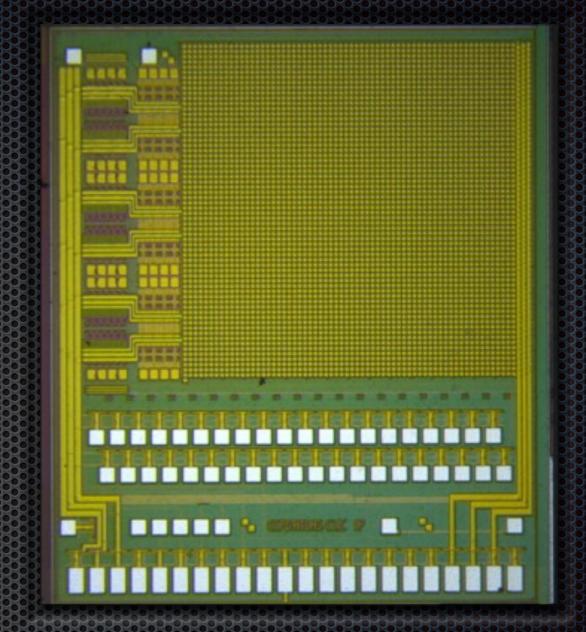


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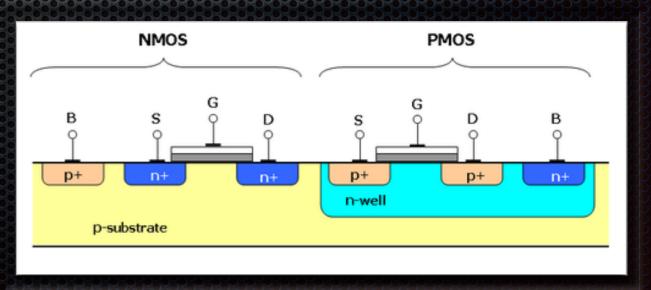
HV-CMOS

- Used by automotive industry
- 2. Cheap
- 3. Multiple suppliers possible

BUT,
we need to test them



HV-CMOS chip version 3

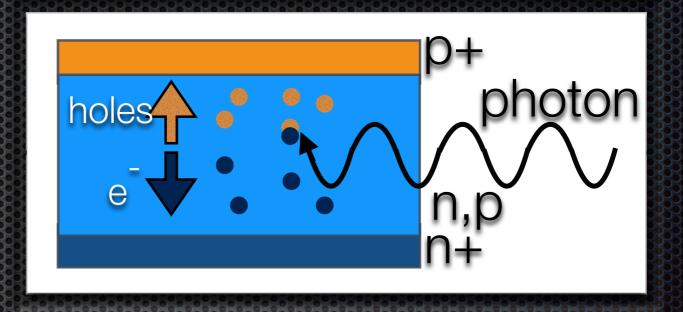


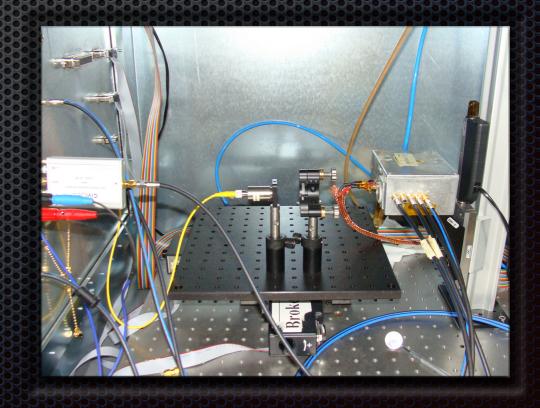
HV-CMOS and Readout

- HV-CMOS chips can be used as pixel or strip detectors
- Active elements provide amplification directly on chip
- Therefore, no separate readout chip is needed in the (distant) future, which reduces the thickness of "dead material", that doesn't record a signal
- No bump-bonding needed

Edge - TCT technique

- Laser light is shone onto the sensor from the side
- Electron Hole pairs are created in the depletion region
- These drift to the top or bottom due to the electric field in the bulk
- This signal is recorded

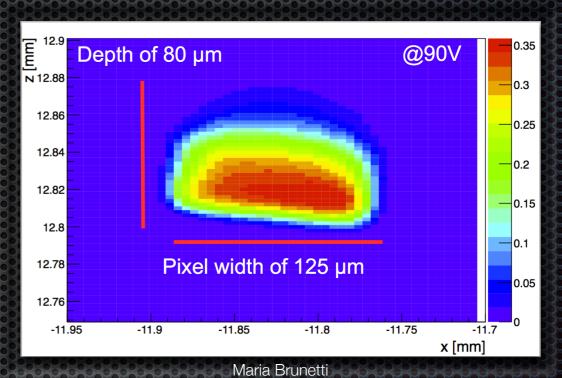


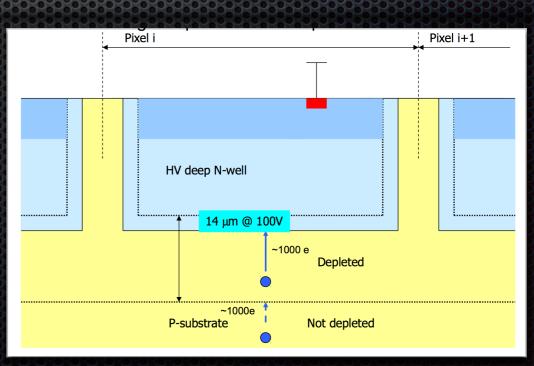


Edge - TCT continued

Monitoring the current pulses over time (transients) can give information about

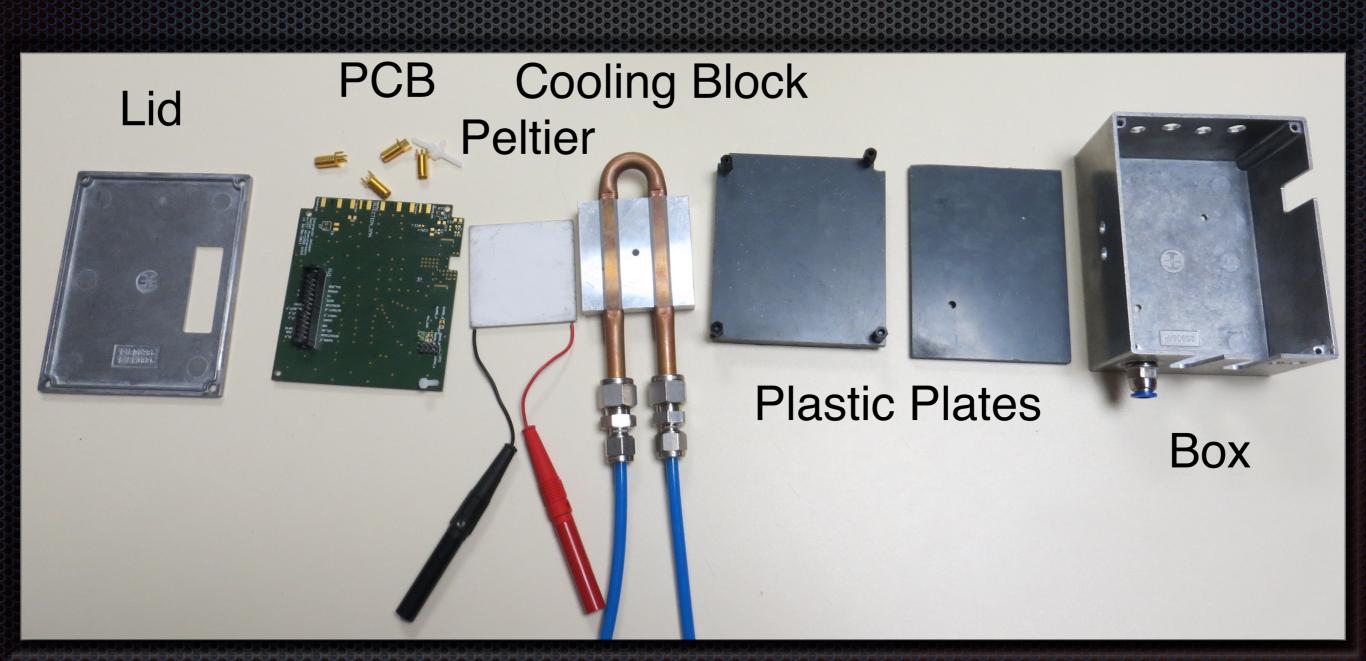
- drift velocity profile
- trapping times
- charge collection efficiency
- depletion voltage



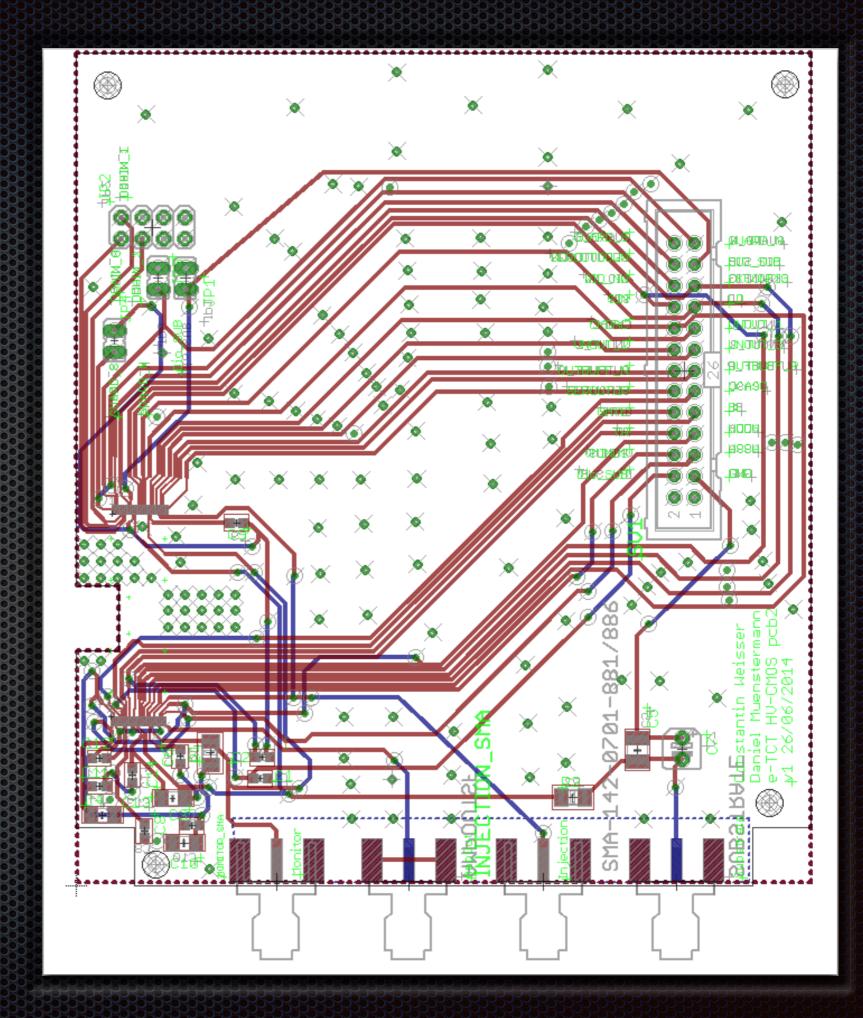


Gregor Kramberger

Integration of the chip into the edge - TCT setup



PCB



How is this different

- Investigation into HV CMOS sensors for particle physics is relatively recent
- Previous HV CMOS chips have been completely characterised, but this third version of the chip hasn't
- The thickness of the charge collection layer has not been measured accurately

Outlook

- The box needs to be integrated into the edge TCT setup
- The charge collection layer thickness will be measured
- The efficiency of sensors at different degrees of radiation will be recorded
- Tests will be performed, whether temperature treatments will increase the collected charge

If favourable results are found this "would open a completely new production method for cost-efficient, large-scale, ultra-fine-pitch pixel and strip detectors."

Daniel Muenstermann

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